

P3A4GL4BLF-GJN

Programmable Functions

Output Driver Impedance (34/48) CAS Write Latency (9/10/11/12/14/16/18) Additive Latency (0/CL-1/CL-2) to Command Address Latency (3/4/5/6/8) Command Address Parity Latency (4/5) Write Recovery Time (10/12/14/16/18/20/24) **Burst Type (Sequential/Interleaved)**

RTT_PARK (34/40/48/60/80/120/240) RTT_NOM (34/40/48/60/80/120/240) RTT_WR (80/120/240) Read Preamble (1T/2T) Write Preamble (1T/2T) LPASR (Manual: Normal/Reduced/Extended, Auto:TS)

Options

Package information

Lead-free RoHS compliance and Halogen-free

TFBGA Package	Dimension (mm)	Ball pitch (mm)
96-Ball	7.50 x 13.00	0.80

Temperature Range $(T_c)^5$

- Commercial Grade : 0°C ~95°C
- Industrial Grade (-I): -40°C ~95°C
- Quasi Industrial Grade (-T) : -40°C ~95°C

VDD/VDDQ/VPP

- 1.2V / 1.2V / 2.5V

NOTE 1 Write Leveling feedback should be given on all data bits in parallel.

NOTE 2 For the same organization and voltage, the timing specification of high speed bin is backward compatible with low speed bin.

NOTE 3 Violating tREFI is not guaranteed.

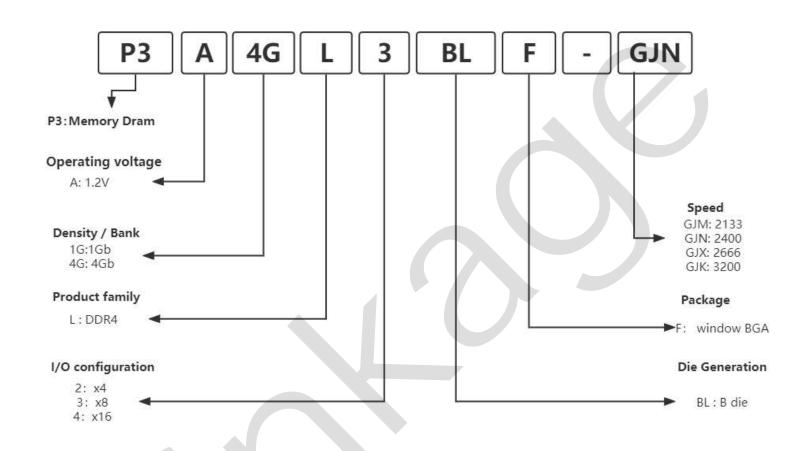
NOTE 4 Violating tRFC is not guaranteed.

NOTE 5 When operate above 95 , AC/DC will be derated.



Ordering Information

4Gb DDR4 ordering information table



	1	2	3	4 5 6	7	8	9	
Α	VDDQ	VSSQ	DQ8		DQ U	VSSQ	VDDQ	Α
В	VPP	VSS	VDD		DQSU	DQ9	VDD	В
C	VDDQ	DQ12	DQ10		DQ11	DQ13	VSSQ	С
D	VDD	VSSQ	DQ14		DQ15	VSSQ	VDDQ	D
E	VSS	UDM/UDBI	VSSQ		LDWLDBI	VSSQ	VSS	Е
F	VSSQ	VDDQ	DQ L		DQ1	VDDQ	ZQ	F
G	VDDQ	DQ0	DQSL		VDD	VSS	VDDQ	G
Н	VSSQ	DQ4	DQ2		DQ3	DQ5	VSSQ	Н
J	VDD	VDDQ	DQ6		DQ7	VDDQ	VDD	J
K	VSS	CKE	ODT		CK	K	VSS	K
L	VDD	WE /A14	АТ			RA /A16	VDD	L
M	VREFCA	BG0	A10/AP		A12 /B	A /A15	VSS	M
N	VSS	BA0	A4		A3	BA1	TEN	N
P	RE ET	A6	A0		A1	A5	ALERT	P
R	VDD	A8	A2		A9	A7	VPP	R
T	VSS	A11	PAR		NC	A13	VDD	Т
	1	2	3	4 5 6	7	8	9	•

Packge Outline Drawing



ymbol	уре	escription
PAR	Input	Parity for command and address: DDR4 Supports Even Parity check in DRAM with MR setting. Once it's enabled via Register in MR5, then DRAM calculates Parity with A T,RA /A16, A /A15,WE/A14, A12/B ,A10/AP, A17-A0, BA0-BA1, BG0-BG1 Command and address inputs shall have parity check performed when commands are latched via the rising edge of CK and when is low.
DQ	Input/output	Data input/output: Bidirectional data bus. DQ represents DQ [3:0], DQ [7:0], and DQ [15:0] for the x16 configurations, respectively. If Write CRC is enabled via Mode register, then the Write CRC code is added at the end of Data Burst. Either anyone or all DQ0, DQ1, DQ2, and DQ3 is used as monitoring of internal Vref level during test via Mode Register Setting MR4 A4=High, training times change when enabled. During this mode, RTT value should be set to Hi-Z. This measurement is for verification purposes and is NOT an external voltage supply pin.
DQS/DQ DQSL/DQ L DQSU/DQ U	Input/output	Data Strobe: Output with READ data, input with WRITE data. Edge-aligned with READ data, centered-aligned with WRITE data. For the x16, DQSL corresponds to the data on DQ [7:0]; DQSU corresponds to the data on DQ [15:8]. DDR4 SDRAM supports a differential data strobe only and does not support a single-ended data strobe.
TDQS/TDQ	Output	Termination Data Strobe: TDQS/TDQ is applicable for X8 DRAMs only. The TDQS function must be disabled in the mode register for x16 configurations. When enabled via Mode Register A11=1 in MR1, DRAM will enable the same R_{TT} termination resistance function on TDQS/TDQ that is applied to DQS/DQ . When the TDQS function is disabled via the mode register, the DM/DBI/TDQS pin will provide the data mask (DM) function or Data Bus Inversion (DBI) depending on MR5, and the TDQ pin is not used.
DM LDM, UDM	Input	Input data mask: DM is an input mask signal for write data. Input data is masked when DM is sampled LOW coincident with that input data during a write access. DM is sampled on both edges of DQS. DM is muxed with DBI function by Mode Register A [12:10] setting in MR5. For x8 device, the function of DM or TDQS is enabled by Mode Register A11 setting in MR1. DBI is an input/output identifying whether to store/output the true or inverted data. If DBI is LOW, the data will be stored/output after inversion inside the DDR4 SDRAM and not inverted if DBI is HIGH.
DBI UDBI, LDBI	Input/output	DBI input/output: Data bus inversion. DBI is an input/output signal used for data bus inversion in the x8 configuration. UDBI and LDBI are used in the x16 configuration; UDBI is associated with DQ [15:8], and LDBI is associated with DQ [7:0]. configurations. DBI can be configured for both READ (output) and WRITE (input) operations depending on the mode register settings. The DM, DBI, and TDQS functions are enabled by mode register settings. See Data Bus Inversion (DBI).
ALERT	Output	Alert output: It has multi functions such as CRC error flag, Command and Address Parity error flag as Output signal. If there is error in CRC, then ALERT goes LOW for the period time interval and goes back HIGH. If there is error in Command Address Parity Check, then ALERT goes LOW for relatively long period until ongoing DRAM internal recovery transaction to complete. During Connectivity Test mode, this pin works as input. Using this signal or not is dependent on system. In case of not connected as Signal, open-drain ALERT Pin must be bounded to VDD on board.
TEN	Input	Connectivity test mode: Connectivity Test Mode is active when TEN is HIGH, and inactive when TEN is LOW. TEN must be LOW during normal operation. TEN is a CMOS rail-to-rail signal with AC HIGH and LOW at 80% and 20% of VDD (960mV for DC HIGH and 240mV for DC LOW). Using this signal or not is dependent on System. This pin may be DRAM internally pulled low through a weak pull-down resistor to VSS.
ZQ	Reference	Reference pin for ZQ calibration: This ball is tied to an external 240 Ω resistor (RZQ), which is tied to VSSQ.
RE ET	Input	Active Low Asynchronous Reset: Reset is active when RE ET is LOW, and inactive when RE ET is HIGH. RE ET must be HIGH during normal operation. RE ET is a CMOS rail to rail signal with DC high and low at 80% and 20% of VDD, i.e. 0.96V for DC high and 0.24V for DC low.

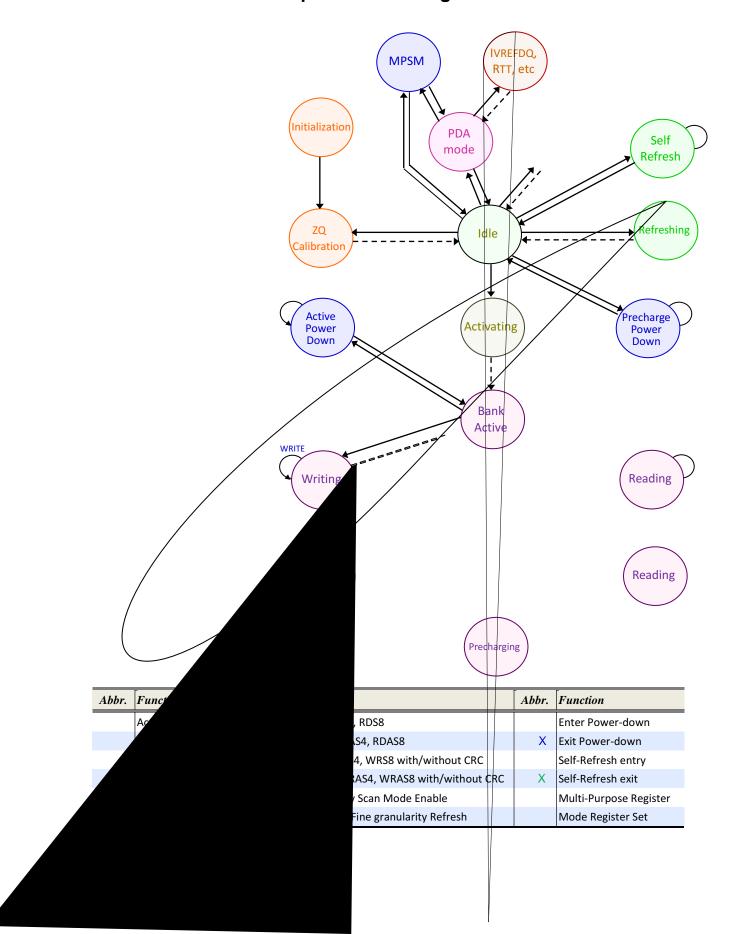


ymbol	уре	escription			
VPP	Supply	RAM activating power supply: 2.5V (2.375V min , 2.75V max)			
VDD	Supply	Power Supply: 1.2V ± 0.06V			
VDDQ	Supply	Q Power Supply: 1.2V ± 0.06V			
VSS	Supply	Ground			
VSSQ	Supply	DQ Ground			
VREFCA	Supply	Reference voltage for CA			
NC	-	No Connect: No internal electrical connection is present.			
NF	-	No function: May have internal connection present, but has no function.			
RFU	-	Reserved for future use.			

NOTE Input only pins (BG0-BG1, BA0-BA1, A0-A17, A T, RA /A16, A /A15, WE/A14, , CKE, ODT, and RE ET) do not supply termination.

Functional Description

Simplified State Diagram





RESET and Initialization Procedure

For power-up and reset initialization, in order to prevent DRAM from functioning improperly, default values for the following MR settings are defined:

Default MR settings for power-up and reset initialization

functions	bits	alue
Gear-down mode	MR3 A[3]=0	1/2 Rate
Per DRAM Addressability	MR3 A[4]=0	Disable
Max Power Saving Mode	MR4 A[1]=0	Disable
to Command/Address Latency	MR4 A[8:6]=000	Disable
CA Parity Latency Mode	MR5 A[2:0]=000	Disable
Hard Post Package Repair Mode	MR4 A[13]=0	Disable
Soft Post Package Repair Mode	MR4 A[5]=0	Disable

Power-Up and Initialization Sequence

The following sequence (Step 1-15) is required for power-up and initialization:

1) Apply power (RE ET and TEN are recommended to be maintained below 0.2 × VDD; all other inputs may be undefined). RE ET needs to be maintained below 0.2 x VDD for minimum 200µs with stable power and TEN needs to be maintained below 0.2 x VDD for minimum 700µs with stable power. CKE is pulled "LOW" any time before RE ET is being deasserted (MIN time 10ns). The power voltage ramp time between 300mV to VDD min must be no greater than 200ms, and during the ramp, VDD ≥ VDDQ and (VDD-VDDQ) < 0.3Volts. VPP must ramp at the same time or earlier than VDD, and VPP must be equal to or higher than VDD at all times.

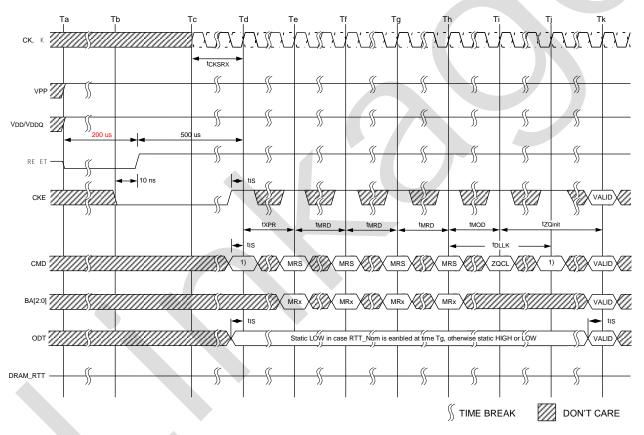
During power-up, either of the following conditions may exist and must be met:

- Condition A
 - VDD and VDDQ are driven from a single-power converter output, AND
 - The voltage levels on all balls other than VDD, VDDQ, VSS, VSSQ must be less than or equal to VDDQ and VDD on one side and must be larger than or equal to VSSQ and VSS on the other side.
 - $-\,\mbox{VTT}$ is limited to 0.76V MAX when the power ramp is finished, AND
 - VREFCA tracks VDD/2.
- Condition B
 - Apply VDD without any slope reversal before or at the same time as VDDQ.
 - Apply VDDQ without any slope reversal before or at the same time as VTT and VREFCA.
 - Apply VPP without any slope reversal before or at the same time as VDD.
 - The voltage levels on all pins other than VDD, VDDQ, VSS, VSSQ must be less than or equal to VDDQ and VDD on one side and must be larger than or equal to VSSQ and VSS on the other side.
- 2) After RE ET is de-asserted, wait for another 500μs until CKE becomes active.
 - During this time, the DRAM will start internal state initialization; this will be done independently of external clocks.
- 3) Clocks (CK, K) need to be started and stabilized for at least 10ns or 5 tCK (whichever is larger) before CKE goes active. Since CKE is a synchronous signal, the corresponding setup time to clock (tIS) must be met. Also a DESELECT command must be registered (with tIS setup time to clock) at clock edge Td. Once the CKE is registered "HIGH" after RESET, CKE needs to be continuously registered "HIGH" until the initialization sequence is finished, including expiration of tDLLK and tZQINIT.
- 4) The DDR4 SDRAM keeps its ODT in High-Impedance state as long as RE ET is asserted. Further, the SDRAM keeps its ODT in High-Impedance state after RE ET deassertion until CKE is registered HIGH. The ODT input signal may be in an undefined state until tIS before CKE is registered HIGH. When CKE is registered HIGH, the ODT input signal may be statically held at either LOW or HIGH. If RTT_NOM is to be enabled in MR1, the ODT input signal must be statically held LOW. In all cases, the ODT input signal remains static until the power-up initialization sequence is



- finished, including the expiration of tDLLK and tZQINIT.
- 5) After CKE is registered HIGH, wait a minimum of RESET CKE EXIT time, tXPR, before issuing the first MRS command to load mode register (tXPR = MAX (tXS; 5 × tCK).
- 6) Issue MRS command to load MR3 with all application settings, wait tMRD.
- 7) Issue MRS command to load MR6 with all application settings, wait tMRD.
- 8) Issue MRS command to load MR5 with all application settings, wait tMRD.
- 9) Issue MRS command to load MR4 with all application settings, wait tMRD.
- 10) Issue MRS command to load MR2 with all application settings, wait tMRD.
- 11) Issue MRS command to load MR1 with all application settings, wait tMRD.
- 12) Issue MRS command to load MRO with all application settings, wait tMOD.
- 13) Issue a ZQCL command to starting ZQ calibration.
- 14) Wait for both tDLLK and tZQINIT completed.
- 15) The DDR4 SDRAM is now ready for read/write training (include Vref training and Write leveling).

RESET and Initialization Sequence at Power-On Ramping



NOTE 1 From the time point Td until Tk, a DES command must be applied between MRS and ZQCL commands.

NOTE 2 MRS commands must be issued to all mode registers that have defined settings.



VDD Slew rate at Power-up Initialization Sequence

VDD Slew Rate

ymbol	in	ax	nits	
sl	0.004	600	V/ms	1,2
_ona		200	ms	3

NOTE 1 Measurement made between 300mV and 80% VDD minimum.

NOTE 2 20 MHz bandlimited measurement

NOTE 3 Maximum time to ramp VDD from 300 mV to VDD minimum.

ES command must be applied between MRS and ZQCL commands. all mode registers that have defined settings.

Linkade



Register Definition

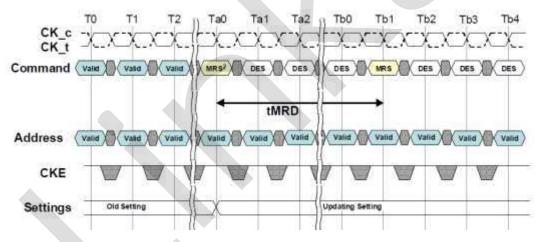
Programming the mode registers

For application flexibility, various functions, features, and modes are programmable in seven Mode Registers, provided by the DDR4 SDRAM, as user defined variables and they must be programmed via a Mode Register Set (MRS) command. The mode registers are divided into various fields depending on the functionality and/or modes. As not all the Mode Registers (MR#) have default values defined, contents of Mode Registers must be initialized and/or re-initialized, i.e. written, after power up and/or reset for proper operation. Also the contents of the Mode Registers can be altered by re-executing the MRS command during normal operation. When programming the mode registers, even if the user chooses to modify only a sub-set of the MRS fields, all address fields within the accessed mode register must be redefined when the MRS command is issued. MRS command and DLL Reset do not affect array contents, which means these commands can be executed any time after power-up without affecting the array contents. MRS Commands can be issued only when DRAM is at idle state. The mode register set command cycle time, tMRD is required to complete the write operation to the mode register and is the minimum time required between two MRS commands.

tMRD Timing

Some of the Mode Register setting affect to address/command/control input functionality. These case, next MRS command can be allowed when the function updating by current MRS command completed.

The MRS commands which do not apply tMRD timing to next MRS command are listed in note 2 of the following figure. These MRS command input cases have unique MR setting procedure, so refer to individual function description.



NOTE 1 This timing diagram depicts C/A Parity Mode "Disabled" case.

NOTE 2 tMRD applies to all MRS commands with the following exceptions:

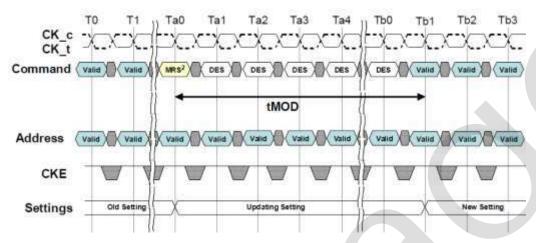
- Geardown Mode
- C/A Parity Latency Mode
- CS to Command/Address Latency Mode
- Per DRAM Addressability Mode
- VrefDQ training value, VrefDQ training mode, and VrefDQ Training Range



tMOD Timing

The MRS command to nonMRS command delay, tMOD, is required for the DRAM to update features, except DLL RESET, and is the minimum time required from an MRS command to a nonMRS command, excluding DES.

Some of the mode register setting cases, function updating takes longer than tMOD. The MRS commands which do not apply tMOD timing to next valid command excluding DES is listed in note 2 of the following figure. These MRS command input cases have unique MR setting procedure, so refer to individual function description.



NOTE 1 This timing diagram depicts C/A Parity Mode "Disabled" case.

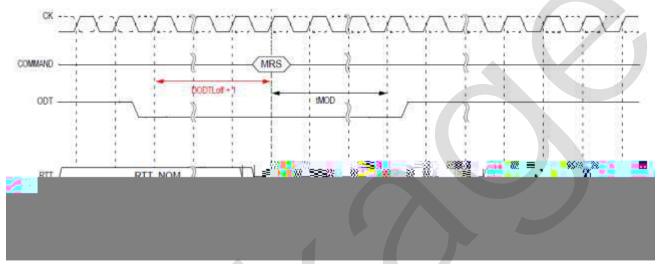
NOTE 2 List of MRS commands exception that do not apply to tMOD.

- DLL Enable, DLL Reset
- VrefDQ training value, internal Vref monitor, VrefDQ training mode, and VrefDQ Training Range
- Geardown Mode
- Per DRAM Addressability Mode
- Maximum Power Saving Mode
- CA Parity Mode



ODT Status at MRS affecting ODT turn-on/off timing

The mode register contents can be changed using the same command and timing requirements during normal operation as long as the DRAM is in idle state, i.e., all banks are in the precharged state with tRP satisfied, all data bursts are completed and CKE is high prior to writing into the mode register. For MRS command, If RTT_Nom function is intended to change (enable to disable and vice versa) or already enabled in DRAM MR, ODT signal must be registered Low ensuring RTT_NOM is in an off state prior to MRS command affecting RTT_NOM turn-on and off timing. Refer to note2 of the following figure for this type of MRS. The ODT signal may be registered high after tMOD has expired. ODT signal is a don't care during MRS command if DRAM RTT_Nom function is disabled in the mode register prior and after an MRS command.



NOTE 1 This timing diagram shows CA Parity Latency mode is "Disable" case.

NOTE 2 When an MRS command mentioned in this note affects RTT_NOM turn on timings, RTT_NOM turn off timings and RTT_NOM value, this means the MR register value changes. The ODT signal should set to be low for at least DODTLoff +1 clock before their affecting MRS command is issued and remain low until tMOD expires. The following MR registers affects RTT_NOM turn on timings, RTT_NOM turn off timings and RTT_NOM value and it requires ODT to be low when an MRS command change the MR register value. If there are no change the MR register value that correspond to commands mentioned in this note, then ODT signal is not require to be low.

- DLL control for precharge power down
- Additive latency and CAS read latency
- DLL enable and disable
- CAS write latency
- CA Parity mode
- Gear Down mode
- RTT_NOM



Mode Register

MR₀

ddress	perating ode	escription				
BG[1]	RFU	0 = mu	st be	progra	mmed to 0	during MRS
BG[0], BA[1:0]	MR Select	0	1	0	elect	
		0	0	0	0	
		0	0	1	MR1	
		0	1	0	MR2	
		0	1	1	MR3	
		1	0	0	MR4	
		1	0	1	MR5	
		1	1	0	MR6	
		1	1	1	RCW ¹	
A[17]	RFU	0 = must be programmed to 0 during MRS				
A[13] ⁵ , A[11:9]	WR and RTP ^{2,3}	See table: Write Recovery and Read to Precharge				
A[8]	DLL Reset	0 = No				
		1 = Yes				
A[7]	TM	0 = No				
A[12, C.4, 2]	CAS Latency ⁴	1 = Tes		AC Late	n ai	
A[12, 6:4, 2]	•			AS Late	ency	
A[3]	Read Burst Type	0 = Sec				
A[1:0]	Burst Length	1 = Interleave			Abbraviated BLS	
A[1.U]	burst Length	00 = 8 (Fixed) Abbreviated BL8 Abbreviated BC40TF or BL80TF				
		01 = BC4 or 8 (on the fly) Abbreviated BC4OTF or BL8OTF 10 = BC4 (Fixed) Abbreviated BC4			Abbreviated BC4	
		11 = Reserved Appreviated BC4			abbicviated bet	

- NOTE 1 Reserved for Register control word setting. DRAM ignores MR command with BG0, BA [1:0] =111 and doesn't respond. When RFU MR code setting is inputted, DRAM operation is not defined.
- NOTE 2 WR (write recovery for autoprecharge) min in clock cycles is calculated by following rounding algorithm. The WR value in the mode register must be programmed to be equal or larger than WRmin. The programmed WR value is used with tRP to determine tDAL.
- NOTE 3 The table shows the encodings for Write Recovery and internal Read command to Precharge command delay. For actual Write recovery timing, please refer to AC timing table.
- NOTE 4 The table only shows the encodings for a given CAS Latency. For actual supported CAS Latency, please refer to speed bin tables for each frequency. CAS Latency controlled by A12 is optional for 4Gb device.
- NOTE 5 A13 for WR and RTP setting is optional for 4Gb.

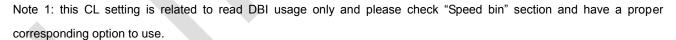
Write Recovery and Read to Precharge (cycles)

13	11	10	9		
0	0	0	0	10	5
0	0	0	1	12	6
0	0	1	0	14	7
0	0	1	1	16	8
0	1	0	0	18	9
0	1	0	1	20	10
0	1	1	0	24	12
0	1	1	1	22	11
1	0	0	0	26	13



CAS Latency

A12	A6	A5	A4	A2	CAS Latency
0	0	0	0	0	Reserved
0	0	0	0	1	Reserved
0	0	0	1	0	11
0	0	0	1	1	12
0	0	1	0	0	13
0	0	1	0	1	14
0	0	1	1	0	15
0	0	1	1	1	16
0	1	0	0	0	18 ⁽¹⁾
0	1	0	0	1	20 ⁽¹⁾
0	1	0	1	0	22 ⁽¹⁾
0	1	0	1	1	24 ⁽¹⁾
0	1	1	0	0	Reserved
0	1	1	0	1	17
0	1	1	1	0	19
0	1	1	1	1	21
1	0	0	0	0	25 ⁽¹⁾
1	0	0	0	1	Reserved
1	0	0	1	0	Reserved
1	0	0	1	1	Reserved
1	0	1	0	0	Reserved
1	0	1	0	1	Reserved
1	0	1	1	0	Reserved
1	0	1	1	1	Reserved
1	1	0	0	0	Reserved





MR1

ddress	perating ode	esci	riptic	n		
BG[1]	RFU	0 = mı	ıst be	progra	mmed to 0 o	during MRS
BG[0], BA[1:0]	MR Select	0	1	0	elect	
		0	0	0	MR0	
		0	0	1	1	
		0	1	0	MR2	
		0	1	1	MR3	
		1	0	0	MR4	
		1	0	1	MR5	
		1	1	0	MR6	
		1	1	1	RCW ³	
A[17]	RFU	0 = mu	ıst be	progra	mmed to 0 d	during MRS
A[13]	RFU	0 = must be programmed to 0 during MRS				
A[12]	Qoff ¹	0 = Output buffer enable				
				ouffer d	isable	
A[11]	TDQS enable	0 = Dis				
		1 = En				
A[10:8]	RTT_NOM			TT_NO	M	
A[7]	Write Leveling Enable	0 = Dis				
A10 51	2511	1 = En	_		1. 0	1 1 100
A[6:5]	RFU				mmed to 0 c	during MRS
A[4:3]	Additive Latency			isabled)		
		01 = C				
		10 = CL-2 11 = Reserved				
A[2:1]	Output Driver Impedance Control					
A[0]	DLL Enable	0 = Dis				
[0]		1 = En				

NOTE 1 Outputs disabled - DQs, DQSs, DQ s.

NOTE 2 States reversed to "0 as Disable" with respect to DDR4.

NOTE 3 Reserved for Register control word setting. DRAM ignores MR command with BG0, BA [1:0] =111 and doesn't respond. When RFU MR code setting is inputted, DRAM operation is not defined.



RTT_NOM

A10	A9	A8	RTT_NOM
0	0	0	Disabled
0	0	1	RZQ/4 (60 Ω)
0	1	0	RZQ/2 (120 Ω)
0	1	1	RZQ/6 (40 Ω)
1	0	0	RZQ/1 (240 Ω)
1	0	1	RZQ/5 (48 Ω)
1	1	0	RZQ/3 (80 Ω)
1	1	1	RZQ/7 (34 Ω)

Output Driver Impedance Control

A2	A 1	ODI
0	0	RZQ/7(34 ohm)
0	1	RZQ/5(48 ohm)
1	0	RFU
1	1	RFU





MR2

ddress	perating ode	escription							
BG[1]	RFU	0 = mu	0 = must be programmed to 0 during MRS						
BG[0], BA[1:0]	MR Select	0	1	0	elect				
		0	0	0	MR0				
		0	0	1	MR1				
		0	1	0	2				
		0	1	1	MR3				
		1	0	0	MR4				
		1	0	1	MR5				
		1	1	0	MR6				
		1	1	1	RCW ¹				
A[17]	RFU	0 = mu	st be p	rogran	nmed to 0 du	ring MRS			
A[13]	RFU	0 = mu	st be p	rogran	nmed to 0 du	ring MRS			
A[12]	Write_CRC	0 = Dis 1 = Ena							
A[11:9]	RTT_WR	See Ta		T_WR					
A[8]	RFU	0 = mu	st be p	rogran	nmed to 0 du	ring MRS			
A[7:6]	Low Power Auto Self Refresh (LPASR)	00 = Manual Mode (Normal Operating Temperature Range) 01 = Manual Mode (Reduced Operating Temperature Range) 10 = Manual Mode (Extended Operating Temperature Range) 11 = ASR Mode (Auto Self Refresh)							
A[5:3]	CAS Write Latency(CWL)	See Table: CWL (CAS Write Latency)							
A[2:0]	RFU	0 = must be programmed to 0 during MRS							

NOTE 1 Reserved for Register control word setting. DRAM ignores MR command with BG0, BA [1:0] =111 and doesn't respond. When RFU MR code setting is inputted, DRAM operation is not defined.



RTT_WR

A11	A10	A9	RTT_WR
0	0	0	Dynamic ODT off
0	0	1	RZQ/2
0	1	0	RZQ/1
0	1	1	Hi-Z
1	0	0	RZQ/3
1	0	1	RFU
1	1	0	RFU
1	1	1	RFU

CAS Write Latency (CWL)

				Speed Grade in MT/s						
A5	A4	А3	CWL	1 tCK t	1 tCK tWPRE 2 tCh		WPRE ¹			
				1st Set	2nd Set	1st Set	2nd Set			
0	0	0	9	1600	-	-	-			
0	0	1	10	1866	<u>-</u>	-	-			
0	1	0	11	2133	1600	-	-			
0	1	1	12	2400	1866	, -	<u>-</u>			
1	0	0	14	2666	2133	2400	-			
1	0	1	16	2933	2400	2666	2400			
1	1	0	18	<u> </u>	2666	2933	2666			
1	1	1	20	-	2933	-	2933			

NOTE 1 The 2 tCK Write Preamble is valid for DDR4-2400/2666/2933 Speed Grade. For the 2nd Set of 2 tCK Write Preamble, no additional CWL is needed.



MR3

ddress	perating ode	escription						
BG[1]	RFU	0 = mu	0 = must be programmed to 0 during MRS					
BG[0], BA[1:0]	MR Select	0 1 0 ele						
		0	0	0	MR0			
		0	0	1	MR1			
		0	1	0	MR2			
		0	1	1	3			
		1	0	0	MR4			
		1	0	1	MR5			
		1	1	0	MR6			
		1	1	1	RCW ¹			
A[17]	RFU	0 = mu	ıst be p	rogran	nmed to 0 du	ring MRS		
A[13]	RFU	0 = mu	ıst be p	rogran	nmed to 0 du	ring MRS		
A[12:11]	MPR Read Format	00 = Serial 01 = Parallel 10 = Staggered 11 = Reserved						
A[10:9]	Write CMD Latency when CRC and DM are enabled	See Ta	ble:		ency when Cl	RC and DM are both enabled		
A[8:6]	Fine Granularity Refresh Mode				ularity Refres			
A[5]	Temperature sensor readout ²	0 = Dis 1 = Ens		7				
A[4]	Per DRAM Addressability	0 = Dis 1 = Ens						
A[3]	Geardown Mode	0 = 1/2 1 = 1/4						
A[2]	MPR Operation	0 = No 1 = Da		from/t	o MPR			
A[1:0]	MPR Page Selection	00 = Page0 01 = Page1 10 = Page2 11 = Page3 See Table: MPR Data Format						

NOTE 1 Reserved for Register control word setting. DRAM ignores MR command with BG0, BA [1:0] =111 and doesn't respond. When RFU MR code setting is inputted, DRAM operation is not defined.

NOTE 2 Please confirm with NTC.



Fine Granularity Refresh Mode

A8	A7	A6	Fine Granularity Refresh Mode
0	0	0	Normal (Fixed 1x)
0	0	1	Fixed 2x
0	1	0	Fixed 4x
0	1	1	RFU
1	0	0	RFU
1	0	1	Enable On-the-fly 1x/2x
1	1	0	Enable On-the-fly 1x/4x
1	1	1	RFU

MR3 A<10:9> Write Command Latency when CRC and DM are both enabled

A10	A9	CRC+DM Write CMD Latency	Operating Data Rate
0	0	4nCK	1600
0	1	5nCK	1866/2133/2400/2666
1	0	6nCK	2933
1	1	RFU	RFU

NOTE 1 Write Command latency when CRC and DM are both enabled

NOTE 2 At less than or equal to 1600 then 4nCK; neither 5nCK nor 6nCK

NOTE 3 $\,$ At greater than 1600 and less than or equal to 2666 then 5nCK; neither 4nCK nor 6nCK



MPR Data Format

3						it rite	ocation	[7:0]			
			7	6	5	4	3	2	1	0	ote
age	urpose	e ocation [1:0]		ead urst rder (serial mode)							
[1:0]		[1.0]	0	1	2	3	4	5	6	7	
		00 = MPR0	0	1	0	1	0	1	0	1	
00	Training	01 = MPR1	0	0	1	1	0	0	1	1	4.2
Page 0 Patterns	10 = MPR2	0	0	0	0	1	1	1	1	1,2	
		11 = MPR3	0	0	0	0	0	0	0	0	
		00 = MPR0	A7	A6	A5	A4	А3	A2	A1	A0	
		01 = MPR1	A /A15	WE /A14	A13	A12	A11	A10	A9	A8	
01	C/A Parity	10 = MPR2	PAR	АТ	BG1	BG0	BA1	BA0	A17 ⁶	RA /A16	3,4,5,6
Page 1	Error Log			CA Parity	CA	Parity Later	ncy ⁶				3,4,3,0
		11 = MPR3	CRC Error Status	Error	MR5	MR5	MR5	-	-	-	
				Status	A2	A1	A0				
		00 = MPR0	hPPR	sPPR	RTT_WR		Temperature Sensor Status ⁸		CRC Write Enable R _Π _WR		
			-	-	MR2			MR2 MI		R2	
			-	-	A11	Refer to i	Refer to next table		A10	A9	
		04 AADD4	Vref DQ range			Vref DQ tra	ining Value			Geardown Enable	
10	MRS	01 = MPR1	MR6			М	R6			MR3	
Page 2	Readout		A6	A5	A4	АЗ	A2	A1	A0	А3	
					CAS Latency			CAS	Write Late	ncy	
		10 = MPR2			MR0				MR2		
			A6	A5	A4	A2	A12	A5	A4	А3	
				R _{TT} _NOM			R _{TT} _PARK		Driver Impedance		
		11 = MPR3		MR1			MR5	1		R1	
			A10	A9	A6	A8	A7	A6	A2	A1	
		00 = MPR0				Don'	t care				
11	Vendor	01 = MPR1				Don'	t care				7
Page 3	use only ⁷	10 = MPR2		Don't care							,
		11 = MPR3				Don'	t care				

- NOTE 1 MPRx using A7:A0 that A7 is mapped to location [7] and A0 is mapped to location [0].
- NOTE 2 Training pattern be defined by MPR0-MPR3 which are default value of Page 0 read and write
- NOTE 3 MPR used for C/A parity error log readout is enabled by setting A [2] in MR3
- NOTE 4 For higher density of DRAM, where A [17] is not used, MPR2[1] should be treated as don't care.
- NOTE 5 If a device is used in monolithic application, where C [2:0] are not used, then MPR3[2:0] should be treated as don't care.
- NOTE 6 MPR3 bit 0~2 (CA parity latency) reflects the latest programmed CA parity latency values.
- NOTE 7 MPR page3 is specifically assigned to DRAM. Actual encoding method is vendor specific.
- NOTE 8 Please confirm with NTC.



Temperature Sensor Status

MPR0 bit A4	MPR0 bit A3	Refresh Rate Range	MR3[5]
0	0	Sub 1x refresh (>tREFI)	MR3 bit A5=1 (Temperature sensor readout = Enabled)
0	1	1x refresh rate (= tREFI)	DRAM updates the temperature sensor status to MPR Page 2 (MPR0 bits A [4:3]). Temperature data is guaranteed by the DRAM to be no more than 32ms old at the time of MPR Read of the Temperature
1	0	2x refresh rate (1/2 x tREFI)	Sensor Status bits. MR3 bit A5=0 (Temperature sensor readout = Disabled)
1	1	RFU	DRAM disables updates to the temperature sensor status in MPR Page 2(MPR0-bit A[4:3])



MR4

ddress	perating ode	escription							
BG[1]	RFU	0 = mu	st be p	rogran	nmed to 0 du	ring MRS			
BG[0], BA[1:0]	MR Select	0	1	0	elect				
		0	0	0	MR0				
		0	0	1	MR1				
		0	1	0	MR2				
		0	1	1	MR3				
		1	0	0	4				
		1	0	1	MR5				
		1	1	0	MR6				
		1	1	1	RCW ¹				
A[17]	RFU	0 = mu	st be p	rogran	nmed to 0 du	ring MRS			
A[13]	hPPR	0 = Dis	able						
		1 = Ena	able						
A[12]	Write Preamble	0 = 1 n							
		1 = 2 n							
A[11]	Read Preamble	0 = 1 n							
A[10]	Dood Ducomble Toning Mode	1 = 2 n 0 = Dis							
A[10]	Read Preamble Taring Mode	1 = Ena							
A[9]	Self Refresh Abort	0 = Dis							
[-]		1 = Ena							
A[8:6]	CS to CMD/ADDR Latency Mode (Cycles)	See Ta	ble: CS	to CM	D/ADDR Late	ncy Mode Setting			
A[5]	sPPR	0 = Dis	able						
		1 = Ena	able						
A[4]	Internal Vref Monitor	0 = Dis	able						
		1 = Ena	able						
A[3]	Temperature Controlled Refresh	0 = Dis							
	Mode	1 = Ena							
A[2]	Temperature Controlled Refresh	0 = No							
Λ[1]	Range Maximum Power Down Mode	1 = Ext 0 = Dis							
A[1]	iviaximum Power Down Mode								
A[0]	RFU	1 = Enable 0 = must be programmed to 0 during MRS							
ا الا	III O	0 – IIIu			ninea to o aai				

NOTE 1 Reserved for Register control word setting. DRAM ignores MR command with BG0, BA [1:0] =111 and doesn't respond. When RFU MR code setting is inputted, DRAM operation is not defined.



CS to CMD / ADDR Latency Mode Setting

A8	A7	A6	CAL
0	0	0	Disabled
0	0	1	3
0	1	0	4
0	1	1	5
1	0	0	6
1	0	1	8
1	1	0	Reserved
1	1	1	Reserved





MR5

ddress	perating ode	escription							
BG[1]	RFU	0 = mu	0 = must be programmed to 0 during MRS						
BG[0], BA[1:0]	MR Select	0	1	0	elect				
		0	0	0	MR0				
		0	0	1	MR1				
		0	1	0	MR2				
		0	1	1	MR3				
		1	0	0	MR4				
		1	0	1	5				
		1	1	0	MR6				
		1	1	1	RCW ¹				
A[17]	RFU	0 = mu	st be p	rogran	nmed to 0 du	ring MRS			
A[13]	RFU	0 = mu	st be p	rogran	nmed to 0 du	ring MRS			
A[12]	Read DBI	0 = Dis	able						
		1 = Ena							
A[11]	Write DBI	0 = Dis							
A [4 O]	5	1 = Ena							
A[10]	Data Mask	0 = Dis 1 = Ena							
A[9]	CA Parity Persistent Error	0 = Dis	-						
, ,[5]	ortrainty rensistent ziron	1 = Ena							
A[8:6]	RTT_PARK	See Ta	ble: RT	T_PAR	K				
A[5]	ODT Input Buffer during	0 = OD	T input	t buffer	is activated				
	Power Down Mode	1 = OD	T input	t buffer	is deactivate	ed			
A[4]	C/A Parity Error Status	0 = Cle							
4.503	0005	1 = Err							
A[3]	CRC Error Clear	0 = Cle							
A[2:0]	C/A Parity Latency Mode	1 = Error							
A[2.0]	C/A Failty Latericy Wiode	See Table: C/A Parity Latency Mode							

NOTE 1 Reserved for Register control word setting. DRAM ignores MR command with BG0, BA [1:0] =111 and doesn't respond. When RFU MR code setting is inputted, DRAM operation is not defined.

NOTE 2 When RTT_NOM Disable is set in MR1, A5 of MR5 will be ignored.



RTT_PARK

A8	A7	A 6	RTT_PARK
0	0	0	RTT_PARK Disabled
0	0	1	RZQ/4
0	1	0	RZQ/2
0	1	1	RZQ/6
1	0	0	RZQ/1
1	0	1	RZQ/5
1	1	0	RZQ/3
1	1	1	RZQ/7

C/A Parity Latency Mode

A2	A 1	A0	CA Parity Latency	Speed Bin
0	0	0	Disabled	
0	0	1	4	1600/1866/2133
0	1	0	5	2400/2666
0	1	1	6	2933
1	0	0	8	RFU
1	0	1	Reserved	
1	1	0	Reserved	
1	1	1	Reserved	

NOTE 1 Parity latency must be programmed according to timing parameters by speed grade table.